IN THE CLAIMS:

Please amend the claims as follows:

- 1-22. (Canceled)
- 23. (Currently Amended) A pixel, comprising: a single-layered substrate further comprising:
 - a generally planar surface having an upper surface comprising semiconductive material having an impurity concentration the greatest at the upper surface of the generally planar surface;
 - at least one protuberance formed from said generally planar surface into the substrate, the

 at least one protuberance having an apex substantially formed from a portion of

 said generally planar surface; and
 - an impurity offset from the apex of the at least one protuberance formed from a portion of said generally planar surface and within said protuberance, said impurity within said protuberance having has a concentration decreasing concurrently with a distance from the apex substantially formed from a portion upper surface of said generally planar surface.
- 24. (Previously Presented) The pixel in claim 23, wherein said impurity is located within said protuberance to the exclusion of said substrate.
- 25. (Currently Amended) A field emission display, comprising:
 a remaining portion of a single-layered substrate, the remaining portion being an uncontaminated single-layered substrate that is at least semiconductive formed from a single-layered substrate having an upper surface, the single-layered substrate having an impurity concentration greatest at the upper surface while decreasing with a distance from the upper surface; and

- a micro-cathode <u>located in a portion of on</u> said substrate formed from the portion of the singlelayered substrate having an impurity concentration greatest at the upper surface thereof, further comprising:
 - a contaminated apex having an impurity concentration substantially the same as portion substantially the same as a portion of the single-layered substrate at the upper surface thereof; and
 - a decreasingly contaminated body, the concentrate concentration of the impurity decreasing from the contaminated apex.
- 26. (Previously Presented) The field emission display of claim 25, wherein said micro-cathode is integral with said substrate.
 - 27. (Currently Amended) A display panel, comprising:
- a generally uncontaminated substrate comprising semiconductive material formed from a single-layered substrate having an upper surface, the single-layered substrate having an impurity concentration greatest at the upper surface while decreasing with a distance from the upper surface; and
- an emitter electrode <u>located in a portion of on</u> said substrate, further comprising an apex having an impurity concentration substantially the same as portion the same as a portion of the single-layered substrate at the upper surface thereof, and further having an etch-resistible quality that increases with depth from said apex.
- 28. (Previously Presented) The display panel in claim 27, wherein said emitter electrode further comprises a base and further has an oxidizable quality that increases with elevation from said base.
- 29. (Previously Presented) The display panel in claim 28, wherein a portion of said substrate that is under said emitter electrode has an etch-resistible quality generally similar to an etch-resistible quality of said base.

30. (Previously Presented) The display panel in claim 29, wherein said portion has an oxidizable quality generally similar to an oxidizable quality of said base.

31-32. (Canceled)